Product data sheet

1. General description

WG40S65HFW1 uses advanced Fine Trench Field-stop IGBT technology with antiparallel diode in TO247 package to provide extremely low Vce(sat), and excellent switching performance. This device offers Best-in-Class efficiency in hard switching and resonant topology.



2. Features and benefits

- Maximum junction temperature 175°C
- · Positive temperature efficient for easy paralleling
- · Very soft, fast recovery anti-parallel diode
- · High speed switching
- · EMI improved Design

3. Applications

- PFC
- Solar Converters
- UPS
- Welding Converters
- · Mid to high range switching frequency converters

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter		Notes	Value			Unit
V _{CE}	Collector-emitter voltage, T _j ≥	Collector-emitter voltage, T _j ≥ 25 °C		650			V
I _C	DC collector current, limited by $T_{j(max)}$ $T_C = 100 ^{\circ}C$				40		A
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static characteristics							
V _{CE(sat)}	Collector-emitter saturation voltage	$V_{GE} = 15 \text{ V}; I_{C} = 40 \text{ A}; T_{J} = 25 \text{ °C}$		-	1.75	2.2	V

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		•C
2	С	collector		
3	E	emitter		
mb	С	mounting base; connected to collector	TO247	G E sym200

6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
WG40S65HFW1	TO247	WG40S65HFW1Q	Tube	30	TO247P	09-Mar-2023

7. Marking

Table 4. Marking codes

Type number	Marking codes
WG40S65HFW1	G40S65 HFW1

8. Limiting values

Table 5. Limiting values

Symbol	Parameter	Notes	Value	Unit
V _{CE}	Collector-emitter voltage, T _j ≥ 25 °C		650	V
I _c	DC collector current, limited by $T_{j(max)}$ $T_c = 25 ^{\circ}\text{C}$ $T_c = 100 ^{\circ}\text{C}$		80 40	А
I _{C(puls)}	Pulsed collector current, t _p limited by T _{j(max)}		120	А
-	Turn off safe operating area $V_{CE} \le 650 \text{ V}, T_j \le 175 ^{\circ}\text{C}, t_p = 1 \mu\text{s}$		120	А
l _F	Diode forward current, limited by $T_{j(max)}$ T_{c} = 25 °C T_{c} = 100 °C		80 40	А
I _{Fpuls}	Diode pulsed current, t _p limited by T _{j(max)}		120	Α
V_{GE}	Gate-emitter voltage		±20	V
P _{tot}	Power dissipation $T_C = 25 ^{\circ}\text{C}$ Power dissipation $T_C = 100 ^{\circ}\text{C}$		312 156	W
T _{stg}	Storage temperature		-55 to +150	°C
T_{jmax}	Maximum operating junction temperature		175	°C
-	Peak soldering temperture		260	°C
M	Mounting Torque with washer		0.55	Nm

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R _{th(j-c)}	IGBT thermal resistance from junction to case			-	0.48	-	K/W
R _{th(j-c)}	Diode thermal resistance from junction to case			-	0.94	-	K/W
R _{th(j-a)}	thermal resistance from junction to ambient			-	40	-	K/W

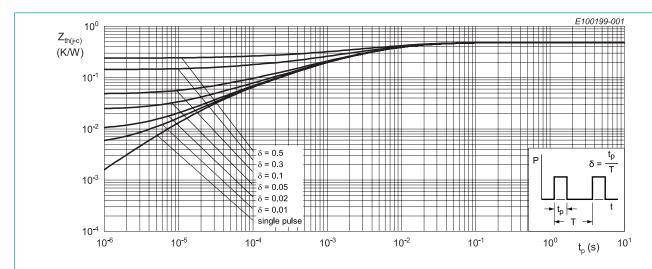


Fig. 1. Transient thermal impedance from junction to case as a function of pulse duration; IGBT

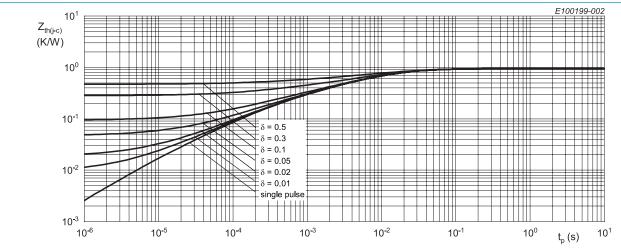


Fig. 2. Transient thermal impedance from junction to case as a function of pulse duration; Diode

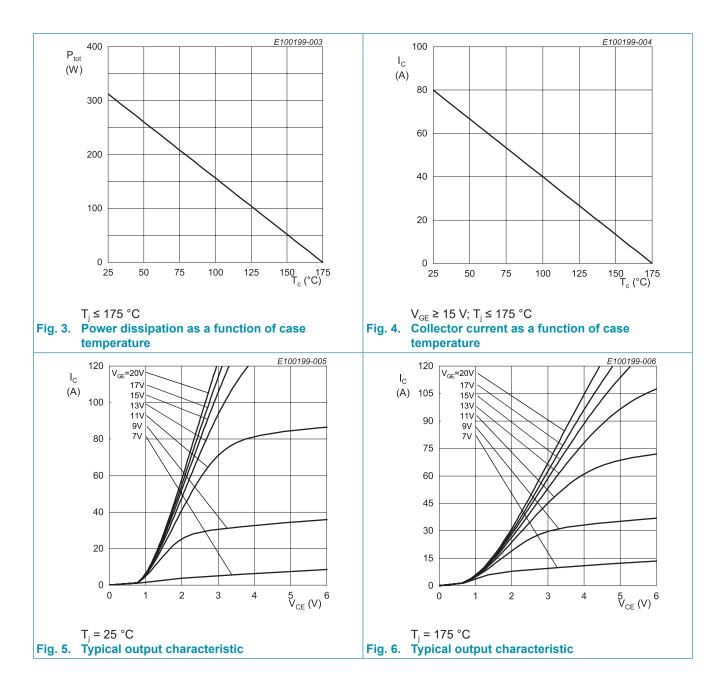
10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static cha	racteristics						
BV_CES	Collector-emitter breakdown voltage	$V_{GE} = 0 \text{ V}; I_{C} = 1.0 \text{ mA}$		650	-	-	V
V _{CE(sat)}	Collector-emitter saturation	V_{GE} = 15 V; I_{C} = 40 A; T_{j} = 25 °C		-	1.75	2.2	V
	voltage	V_{GE} = 15 V; I_{C} = 40 A; T_{j} = 175 °C		-	2.4	-	V
V _F	Diode forward voltage	$V_{GE} = 0 \text{ V}; I_F = 40 \text{ A}; T_j = 25 \text{ °C}$		-	2.05	-	V
		$V_{GE} = 0 \text{ V}; I_F = 40 \text{ A}; T_j = 175 \text{ °C}$		-	1.73	-	V
$V_{\text{GE(th)}}$	Gate-emitter threhold voltage	$I_{\rm C}$ = 0.5 mA; $V_{\rm CE}$ = $V_{\rm GE}$		4.3	5.4	6.5	V
I _{CES}	Zero gate voltage collector current	$V_{CE} = 650 \text{ V}; V_{GE} = 0 \text{ V}; T_j = 25 \text{ °C}$		-	-	100	μA
		$V_{CE} = 650 \text{ V}; V_{GE} = 0 \text{ V}; T_j = 175 ^{\circ}\text{C}$		-	-	1	mA
g _{fs}	Transconductance	V _{CE} = 20 V; I _C = 40 A		-	22	-	S
Dynamic	characteristics						
C _{ies}	Input capacitance	$V_{CE} = 30 \text{ V}; V_{GE} = 0 \text{ V}; f = 1 \text{ MHz};$		-	1638	-	pF
C _{oes}	Output capacitance	T _j = 25 °C		-	65	-	pF
C _{res}	Reverse transfer capacitance			-	19	-	pF
Q_{G}	Gate charge	V_{CC} = 520 V; I_{C} = 40 A; V_{GE} = 15 V; T_{i} = 25 °C		-	74	-	nC

11. Switching Characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
IGBT cha	racteristics						
$t_{d(on)}$	Turn-on delay time	T _j = 25 °C;		-	32	-	nS
t _r	Rise time	$V_{CC} = 400 \text{ V}; I_C = 40 \text{ A};$ $V_{GE} = 15 \text{ V} / 0 \text{ V};$		-	45	-	nS
$t_{d(off)}$	Turn-off delay time	$R_G = 10 \Omega$		-	112	-	nS
t _f	Fall time			-	25	-	nS
E _{on}	Turn-on energy			-	1.1	-	mJ
E _{off}	Turn-off energy			-	0.45	-	mJ
E _{ts}	Total switching energy			-	1.55	-	mJ
t _{d(on)}	Turn-on delay time	T _j = 175 °C;		-	33	-	nS
t _r	Rise time	$V_{CC} = 400 \text{ V}; I_{C} = 40 \text{ A};$ $V_{GE} = 15 \text{V} / 0 \text{V};$		-	43	-	nS
$t_{d(off)}$	Turn-off delay time	$R_G = 10 \Omega$		-	135	-	nS
t _f	Fall time			-	32	-	nS
E _{on}	Turn-on energy			-	1.75	-	mJ
E _{off}	Turn-off energy			-	0.65	-	mJ
E _{ts}	Total switching energy			-	2.4	-	mJ
Diode cha	aracteristics		'		'		
t _{rr}	Reverse recovery time	T _j = 25 °C;		-	42	-	nS
Q _r	Reverse recovery charge	$V_R = 400 \text{ V}; I_F = 40 \text{ A};$ $dI_F/dt = 700 \text{A/us}$		-	300	-	nC
I _{RM}	Reverse recovery peak current			-	13	-	А
t _{rr}	Reverse recovery time	T _j = 175 °C;		-	121	-	nS
Q _r	Reverse recovery charge	$V_R = 400 \text{ V}; I_F = 40 \text{ A};$ $dI_F/dt = 700 \text{A/us}$		-	1318	-	nC
I _{RM}	Reverse recovery peak current	- 1-p. 1-1 - 1 - 3 - 3 - 3 - 3 - 3 - 3 - 3 - 3		-	20	-	А



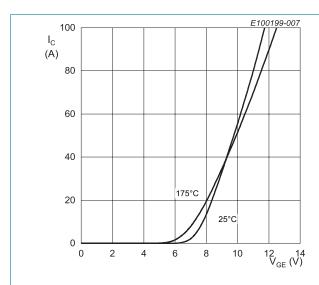


Fig. 7. Typical transfer characteristic

 $V_{CE} = 20 \text{ V}$

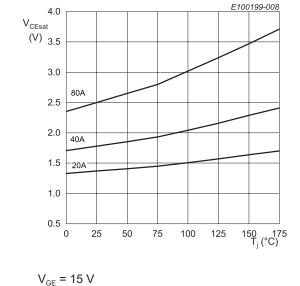
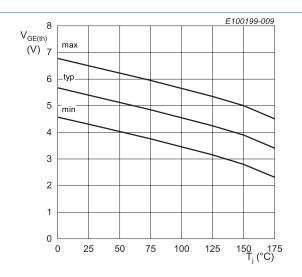
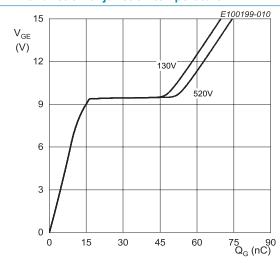


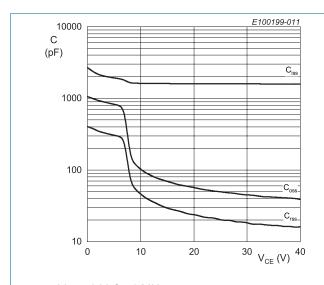
Fig. 8. Typical collector-emitter saturation voltage as a function of junction temperature

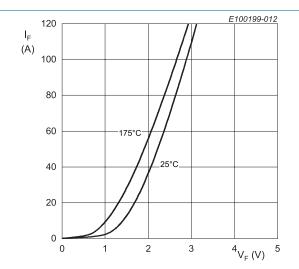


 I_c = 500 μA Fig. 9. Gate-emitter threshold voltage as a function of junction temperature



I_c = 40 A Fig. 10. Typical gate charge

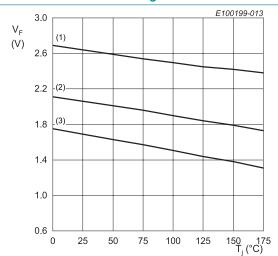


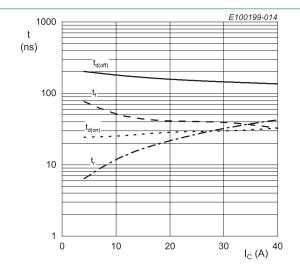


 $V_{GE} = 0 \text{ V}; f = 1 \text{ MHz}$

Fig. 12. Typical diode forward current as a function of forward voltage

Fig. 11. Typical capacitance as a function of collector-emitter voltage





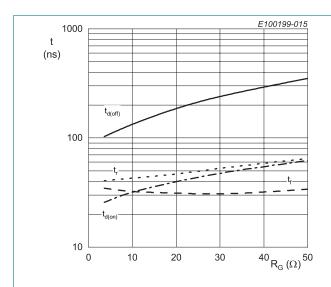
(1) $I_F = 80 \text{ A}$ (2) $I_F = 40 \text{ A}$

(3) I_F = 20 A Fig. 13. Typical diode forward voltage as a function

of junction temperature

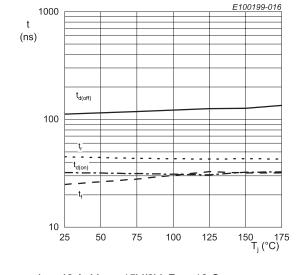
 R_g = 10 Ω ; V_{GE} = 15V/0V; T_j = 175 °C; V_{CE} = 400 V; inductive load

Fig. 14. Typical switching times as a function of collector current



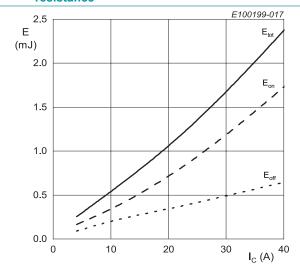
 I_C = 40 A; V_{GE} = 15V/0V; T_j = 175 °C; V_{CE} = 400 V; inductive load

Fig. 15. Typical switching times as a function of gate resistance



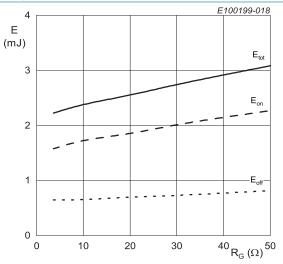
 I_{C} = 40 A; V_{GE} = 15V/0V; R_{g} = 10 Ω ; V_{CE} = 400 V; inductive load

Fig. 16. Typical switching times as a function of junction temperature



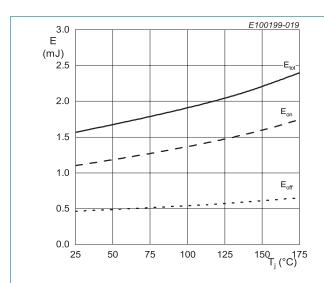
$$\begin{split} R_g = 10~\Omega;~V_{GE} = 15 \text{V/0V};~T_j = 175~^{\circ}\text{C};\\ V_{CE} = 400~\text{V};~inductive~load \end{split}$$
 Fig. 17. Typical switching energy losses as a function

of collector current



 I_{C} = 40 A; V_{GE} = 15V/0V; T_{j} = 175 °C; V_{CE} = 400 V; inductive load

Fig. 18. Typical switching energy losses as a function of gate resistance



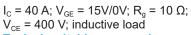


Fig. 20. Forward bias safe operating area



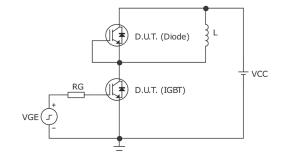


Fig. 21. Test circuit for inductive load switching

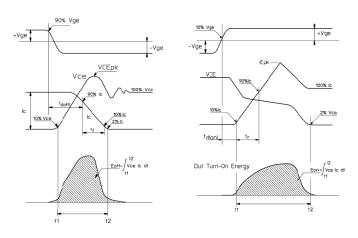
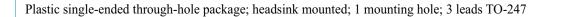
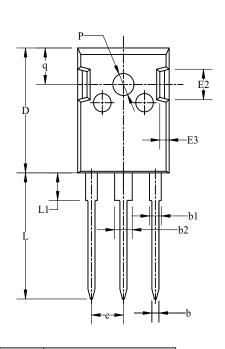


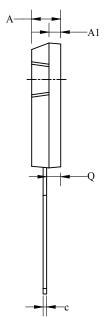
Fig. 22. Definition of switching times and losses

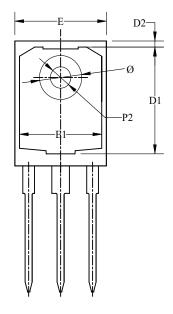
12. Package outline



TO247







Dim	All Dimensions in Millimeters			
Dilli	Min	Тур	Max	
A	4.70	4.95	5.20	
A1	1.90	2.00	2.10	
b	1.00	1.20	1.40	
b1	1.80	2.00	2.20	
b2	2.80	3.00	3.20	
с	0.50	0.60	0.70	
D	20.30	20.45	20.60	
D1	17.28	17.48	17.68	
D2	0.80	1.00	1.20	
Е	15.45	15.60	15.75	
E1	13.82	14.02	14.22	
E2	4.80	5.00	5.20	
E3	1.40	1.60	1.80	
e		5.45 BSC		
L	20.40	20.65	20.90	
L1	4.25	4.50	4.75	
P2	3.40	3.50	3.60	
P	3.50	3.60	3.70	
Q	2.20	2.40	2.60	
q	5.78	5.98	6.18	
Ø	7.10	7.19	7.30	

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13. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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- Please consult the most recently issued document before initiating or completing a design.
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